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(54) **Probe card for testing semiconductor device, and semiconductor device test method**

Testsondenkarte und Testverfahren für eine Halbleitervorrichtung

Carte à sondes pour tester un dispositif semiconducteur et méthode de test

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(73) Proprietor: **Fujitsu Microelectronics Limited**
Tokyo 163-0722 (JP)

(72) Inventor: **Maruyama, Shigeyuki**
Nakahara-ku,
Kawasaki-shi,
Kanagawa 211 (JP)

(74) Representative: **Sunderland, James Harry et al**
Haseltine Lake
Lincoln House
300 High Holborn
London WC1V 7JH (GB)

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